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U.S. UTILITY Patent Application

ISSUE UNIT

APPL NUM 10004168	FILING DATE 10/30/2001	CLASS 438	SUBCLASS 4	GAU 2012	EXAMINER N.F. are
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****CONTINUING DATA VERIFIED:**

** FOREIGN APPLICATIONS VERIFIED:

JAPAN 2000-334915 10/30/2000

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed		<input type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO
35 USC 119 conditions met		<input type="checkbox"/> yes <input type="checkbox"/> no	
Verified and Acknowledged Examiners's initials			
TITLE : Inspection system and semiconductor device manufacturing method			

U.S. DEPT. OF COMM./PAT & TM-PTO-4361 (Rev. 12-24)

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G
ISSUE FEE		DRAWING		
Amount Due	Date Paid	Sheets Drwg.	Figs.Drwg.	Print Fig.
<input type="checkbox"/> TERMINAL DISCLAIMER		Primary Examiner	Application Examiner	
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